

DW  
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: U.S.S.N. 10/676,393

Inventor: Thomas Van Steenkiste, et al.

Title: KINETIC SPRAYED ELECTRICAL CONTACTS ON CONDUCTIVE  
SUBSTRATES

Filed: October 1, 2003

Art Unit: 1762

ATTORNEY DOCKET: DP-300377

Examiner: Unknown

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Mail Stop Non-Fee Amendment, Commissioner For Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on:

5/12/04  
Date

  
Lindsey Dickerson

STATEMENT ACCOMPANYING  
INFORMATION DISCLOSURE STATEMENT

Applicant(s) requests the Examiner to consider and make of record the reference(s) and/or information disclosed herein or on the attached PTO 1449.

**CHECK ONE: (A, B, or C.)**

A. This statement is submitted within 1) three months after the filing date (even if after the first action); or 2) within three months of the date of entry of the national stage or 3) before the mailing date of a first Office Action on the merits. No fee or statement is required.

B. This statement is submitted after the period specified in para. A, but before Final Office Action or Notice of Allowance or the close of prosecution.

**CHECK ONE: (1, 2, or 3)**

1. I hereby state that each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or



**U.S.S.N. 10/616,490 (DP-306711) – 2**

2. I hereby state that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of the information disclosure statement.

3. Charge the \$180 fee set forth in 37 CFR §1.17(p) to Delphi Technologies, Inc. Deposit Account No. 50-0831.

C. This statement is submitted after a Final Office Action or Notice of Allowance or the close of prosecution, but before payment of the issue fee. Charge the \$180 fee set forth in 37 CFR §1.17(p) to Delphi Technologies, Inc. Deposit Account No. 50-0831.

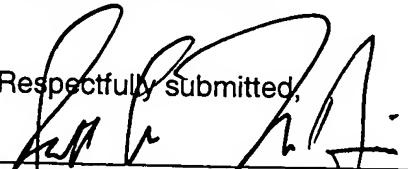
**CHECK ONE: (1 or 2)**

1. I hereby state that each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or

2. I hereby state that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of the information disclosure statement.

If any additional fee or any additional amount of fee be required in connection with this Information Disclosure Statement, Applicant respectfully requests that such fee or amount of fee be charged to Delphi Technologies, Inc. Deposit Account No. 50-0831.

Respectfully submitted,

  
\_\_\_\_\_  
Scott A. McBain – 37,181  
Delphi Technologies, Inc.  
Telephone (248) 813-1235

enc: PTO 1449 and references

**INFORMATION DISCLOSURE CITATION WITH DOCUMENT COPIES**

Atty. Docket No.	Serial No.
DP-300377	10/676393
<hr/>	
Applicant	
THOMAS HUBERT VAN STEENKISTE	
<hr/>	
Filing Date	Group
October 1, 2003	

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

Van Steenkiste, et al; *Kinetic Spray Coatings*; in Surface & Coatings Technology III; 1999, pp. 62-71

Liu, et al; *Recent Development in the Fabrication of Metal Matrix-Particulate Composites Using Powder Metallurgy Techniques*; in Journal of Material Science 29' 1994; pp. 1999-2007; National University of Singapore, Japan

Papyrin; *The Cold Gas-Dynamic Spraying Method a New Method for Coatings Deposition Promises a New Generation of Technologies*; Novosibirsk, Russia.

McCune, et al; Characterization of Copper and Steel Coatings Made by the Cold Gas-Dynamic Spray Method; National Thermal Spray Conference

Alkhimov, et al; *A Method of "Cold" Gas-Dynamic Deposition*; Sov. Phys. Kokl. 36 (12; December 1990; pp. 1047-1049)

Dykuizen, et al; *Impact of High Velocity Cold Spray Particles*; in Journal of Thermal Spray Technology 8 (4); 1999 pp. 559-564

Swartz, et al; *Thermal Reisistance At Interfaces*; Applied Physics Letter, Vol. 51, No. 26, 28; December 1987; pp. 2201-2202

Davis, et al; *Thermal Conductivity of Metal-Matrix Composites*; J. Applied Physics 77 (10), May 15, 1995; pp. 4494-4960

Stoner, et al; *Measurements of the Kapitza Conductance Between Diamond and Several Metals*; Physical Review Letters, Volume 68, Number 10; March 9, 1992; pp. 1563-1566

Stoner, et al; *Kapitza Conductance and Heat Flow Between Solids at Temperatures from 50 to 300K*; Physical Review B, Volume 48, Number 22, December 1, 1993 – II; pp. 16374 – 16387

Johnson, et al; *Diamond/Al Metal Matrix Composites Formed by the Pressureless Metal Infiltration Process*; J. Mater. Res., Vol. 8, No. 5, May 1993; pp. 1169-1173.

Rajan, et al; *Reinforcement Coatings and Interfaces in Aluminum Metal Matrix Composites*; pp. 3491-3503

*LEC Manufacturing and Engineering Components*; Lanxide Electronic Components, Inc.

Dykuizen, et al.; *Gas Dynamic Principles of Cold Spray*; Journal of Thermal Spray Technology; 06-98; pp. 205-212

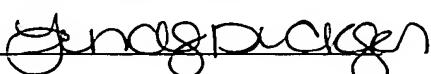
Examiner  Date Considered

**\*Examiner: Initial if reference considered whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.**

Form PTO-FB-A820 (also PTO-1449) Patent & Trademark Office-US Dept. of Commerce

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450 on:

Date: 5/12/04

Signature: 

Name: Lindsey Dickerson

INFORMATION DISCLOSURE CITATION WITH DOCUMENT COPIES

Atty. Docket No.	Serial No.
DP-300377	10/676393
<hr/>	
Applicant	
THOMAS HUBERT VAN STEENKISTE	
<hr/>	
Filing Date	Group
October 1, 2003	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

McCune, et al; *An Exploration of the Cold Gas-Dynamic Spray Method for Several Materials Systems*

Ibrahim, et al; *Particulate Reinforced Metal Matrix Composites – A Review*; *Journal of Materials Science* 26; pp. 1137-1156

I.J. Garshelis, et al; *A Magnetoelastic Torque Transducer Utilizing a Ring Divided into Two Oppositely Polarized Circumferential Regions*; *MMM* 1995; Paper No. BB-08

I.J. Garshelis, et al; *Development of a Non-Contact Torque Transducer for Electric Power Steering Systems*; *SAE Paper No. 920707*; 1992; pp. 173-182

Boley, et al; *The Effects of Heat Treatment on the Magnetic Behavior of Ring – Type Magnetoelastic Torque Sensors*; *Proceedings of Sicon '01*; November 2001

J.E. Snyder, et al; *Low Coercivity Magnetostrictive Material with Giant Piezomagnetic d33*, Abstract Submitted for the MAR99 Meeting of the American Physical Society

McCune, et al; *An Exploration of the Cold Gas-Dynamic Spray Method...*; *Proc. Nat. Thermal Spray Conf. ASM 9/1995*

Pavel Ripka, et al; *Pulse Excitation of Micro-Fluxgate Sensors*, *IEEE Transactions on Magnetics*, Vol. 37, No. 4, July 2001, pp. 1998-2000

Trifon M. Liakopoulos, et al; *Ultrahigh Resolution DC Magnetic Field Measurements Using Microfabricated Fluxgate Sensor Chips*, University of Cincinnati, Ohio, Center for Microelectronic Sensors and MEMS, Dept. of ECECS pp. 630-631

Derac Son, *A New Type of Fluxgate Magnetometer Using Apparent Coercive Field Strength Measurement*, *IEEE Transactions on Magnetics*, Vol. 25, No. 5, September 1989, pp. 3420-3422

O. Dezauri, et al; *Printed Circuit Board Integrated Fluxgate Sensor*, *Elsevier Science S. A. (2000) Sensors and Actuators*, Pp. 200-203

How, et al; *Generation of High-Order Harmonics in Insulator Magnetic Fluxgate Sensor Cores*, *IEEE Transactions on Magnetics*, Vol. 37, No. 4, July 2001, pp. 2448-2450

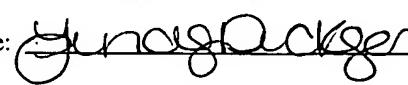
Moreland, *Fluxgate Magnetometer*, Carl W. Moreland, 199-2000, pp. 1-9

Ripka, et al; *Symmetrical Core Improves Micro-Fluxgate Sensors*, *Sensors and Acutuators*, Version 1, August 25, 2000, pp. 1-9

Examiner  Date Considered

**\*Examiner: Initial if reference considered whether or not citation is in conformance with MPEP 609;  
Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.**

Form PTO-FB-A820 (also PTO-1449) Patent & Trademark Office-US Dept. of Commerce

I hereby certify that this correspondence is  Date: 5/12/04  
being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450 on:  Signature:   
Name: Lindsey Dickerson

## **INFORMATION DISCLOSURE CITATION WITH DOCUMENT COPIES**

Atty. Docket No. DP-300377	Serial No. 10/676393
Applicant THOMAS HUBERT VAN STEENKISTE	
Filing Date October 1, 2003	Group

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

Hoton How, et al; *Development of High-Sensitivity Fluxgate Magnetometer Using Single-Crystal Yttrium Iron Garnet Thick Film as the Core Material, ElectroMagnetic Applications, Inc.*

Ripka, et al; *Microfluxgate Sensor with Closed Core*, submitted for Sensors and Actuators, Version 1, June 17, 2000

Henriksen, et al; *Digital Detection and Feedback Fluxgate Magnetometer*, Meas. Sci. Technol. 7 (1996) pp.897-903

Cetek 930580 Compass Sensor, *Specifications*, June 1997

Geyger, *Basic Principles Characteristics and Applications*, Magnetic Amplifier Circuits, 1954, pp. 219-232

Examiner | Date Considered

**\*Examiner: Initial if reference considered whether or not citation is in conformance with MPEP 609;  
Draw line through citation if not in conformance and not considered. Include copy of this form with next  
communication to applicant.**

Form PTO-FB-A820 (also PTO-1449) Patent & Trademark Office-US Dept. of Commerce

I hereby certify that this correspondence is  
being deposited with the United States Postal Service at the Post Office in  
Date: 5/12/04

Service as first class mail in an envelope  
addressed to: Commissioner for Patents  
P.O. Box 1450 Alexandria, Virginia 22313-1450 on: Signature:   
Name: Lindsey Dickerson

Name: Lindsey Dickerson